


<b>Search Notes</b>  	<b>Application/Control No.</b>  10559659	<b>Applicant(s)/Patent Under Reexamination</b>  KATO ET AL.
	<b>Examiner</b>  HUY D NGUYEN	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
455	456.1, 412.1, 435.1, 554.2	9/26/2008	HN
370	310, 346	9/26/2008	HN
Updated search	same above	3/29/2009	HN

SEARCH NOTES		
Search Notes	Date	Examiner
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	9/26/2008	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	3/29/2009	HN
consulted with Steve D'Agosta and Tai Nguyen	3/29/2009	HN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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